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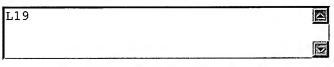
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<u>L13</u>	19 and 12	20	<u>L13</u>	
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<u>L10</u>	15 with 18	124	<u>L10</u>	
<u>L9</u>	15 same 18	171	<u>L9</u>	
<u>L8</u>	16 with 17	4743	<u>L8</u>	
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<u>L6</u>	node	315283	<u>L6</u>	
<u>L5</u>	13 near2 L4	2096	<u>L5</u>	
<u>L4</u>	request\$ or command	910638	<u>L4</u>	
<u>L3</u>	invalidat\$	22955	<u>L3</u>	
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1 Scalable consistency protocols for distributed services

Ahamad, M.;

Parallel and Distributed Systems, IEEE Transactions on , Volume: 10 , Issue:

9 , Sept. 1999

Pages:888 - 903

[Abstract] [PDF Full-Text (496 KB)]

2 Buffer analysis for a data sharing environment with skewed data access

Dan, A.; Dias, D.M.; Yu, P.S.;

Knowledge and Data Engineering, IEEE Transactions on , Volume: 6 , Issue:

2 , April 1994

Pages: 331 - 337

[Abstract] [PDF Full-Text (720 KB)] **IEEE JNL**

3 A novel multicast scheme to reduce cache invalidation overheads in DSM systems

Zhiyu Zhou; Weisong Shi; Zhimin Tang;

Performance, Computing, and Communications Conference, 2000. IPCCC '00.

Conference Proceeding of the IEEE International, 20-22 Feb. 2000

Pages: 597 - 603

[PDF Full-Text (508 KB)] [Abstract] **IEEE CNF**

4 The use of prediction for accelerating upgrade misses in cc-NUMA multiprocessors

Acacio, M.E.; Gonzalez, J.; Garcia, J.M.; Duato, J.;

Parallel Architectures and Compilation Techniques, 2002. Proceedings. 2002

International Conference on , 22-25 Sept. 2002

Pages: 155 - 164

[PDF Full-Text (349 KB)] [Abstract] **IEEE CNF**

5 A performance evaluation of tree-based coherent distributed shared memory

Wada, K.; Obata, M.; Nakamura, M.; Yamazaki, T.; Communications, Computers and Signal Processing, 1993., IEEE Pacific Rim

Conference on , Volume: 2 , 19-21 May 1993

Pages:390 - 393 vol.2

[Abstract] [PDF Full-Text (268 KB)] IEEE CNF

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